

3.3V CMOS Static RAM 1 Meg (128K x 8-Bit) Center Power & Ground Pinout

Features

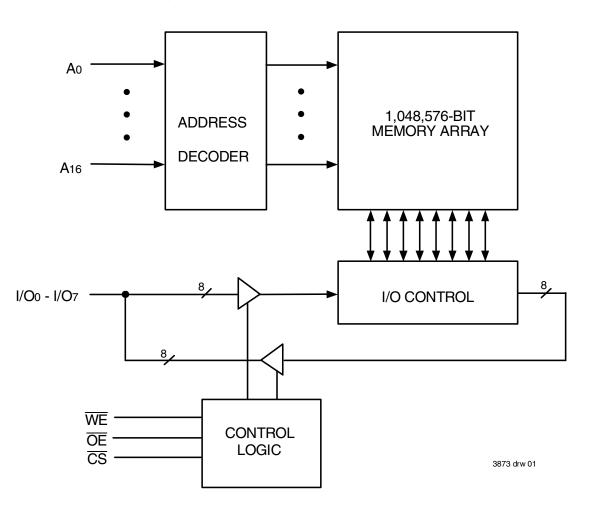
- 128K x 8 advanced high-speed CMOS static RAM
- JEDEC revolutionary pinout (center power/GND) for reduced noise
- Equal access and cycle times
- Commercial: 10/12/15ns
 - Industrial: 12/15ns
- One Chip Select plus one Output Enable pin
- Inputs and outputs are LVTTL-compatible
- Single 3.3V supply
- Low power consumption via chip deselect
- Available in a 32-pin 300- and 400-mil Plastic SOJ, and 32-pin Type II TSOP packages.

Functional Block Diagram

Description

The IDT71V124 is a 1,048,576-bit high-speed static RAM organized as 128K x 8. It is fabricated using high-performance, high-reliability CMOS technology. This state-of-the-art technology, combined with innovative circuit design techniques, provides a cost-effective solution for high-speed memory needs. The JEDEC center power/GND pinout reduces noise generation and improves system performance.

The IDT71V124 has an output enable pin which operates as fast as 5ns, with address access times as fast as 10ns available. All bidirectional inputs and outputs of the IDT71V124 are LVTTL-compatible and operation is from a single 3.3V supply. Fully static asynchronous circuitry is used; no clocks or refreshes are required for operation.

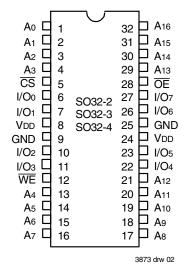


FEBRUARY 2013

IDT71V124SA, 3.3V CMOS Static RAM 1 Meg (128K x 8-Bit) Center Power & Ground Pinout

Commercial and Industrial Temperature Ranges

Pin Configuration



SOJ and TSOP Top View

Truth Table⁽¹⁾

CS	ŌĒ	WE	I/O	Function
L	L	Н	DATAOUT	Read Data
L	Х	L	DATAIN	Write Data
L	Н	Н	High-Z	Output Disabled
Н	Х	Х	High-Z	Deselected – Standby

NOTE:

1. $H = V_{IH}, L = V_{IL}, X = Don't care.$

Capacitance

(TA = +25°C, f = 1.0MHz, SOJ package)

Symbol	Parameter ⁽¹⁾	Conditions	Max.	Unit
Cin	Input Capacitance	VIN = 3dV	6	pF
Cvo	I/O Capacitance	Vout = 3dV	7	pF
				3873 tbl 03

NOTE:

1. This parameter is guaranteed by device characterization, but is not production tested.

Absolute Maximum Ratings⁽¹⁾

Symbol	Rating Value		Unit	
Vdd	Supply Voltage Relative to GND	-0.5 to +4.6	V	
Vin, Vout	Terminal Voltage Relative to GND	-0.5 to VDD+0.5	V	
Тл	Commercial Operating Temperature	-0 to +70	°C	
Та	Industrial Operating Temperature	-40 to +85	Ĵ	
Tbias	Temperature Under Bias	-55 to +125	٥C	
Tstg	Storage Temperature	-55 to +125	٥C	
Рт	Power Dissipation	1.25	W	
Ιουτ	DC Output Current	50	mA	

NOTE:

3873 tbl 01

 Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

Recommended Operating Temperature and Supply Voltage

Grade	Temperature	GND	Vdd
Commercial	0°C to +70°C	0V	See Below
Industrial	-40°C to +85°C	0V	See Below

3873 bl 02a

3873 tbl 04

3873 tbl 02

Recommended DC Operating Conditions

Symbol	Parameter	Min.	Тур.	Max.	Unit
Vdd ⁽¹⁾	Supply Voltage	3.15	3.3	3.6	V
Vdd ⁽²⁾	Supply Voltage	3.0	3.3	3.6	V
Vss	Ground	0	0	0	V
Viн	Input High Voltage	2.0		VDD+0.3 ⁽³⁾	V
VIL	Input Low Voltage	-0.5(1)		0.8	V

NOTES:

1. For 71V124SA10 only.

2. For all speed grades except 71V124SA10.

3. VIH (max.) = VDD+2V for pulse width less than 5ns, once per cycle.

4. V_{IL} (min.) = -2V for pulse width less than 5ns, once per cycle.

DC Electrical Characteristics

(VDD = Min. to Max., Commercial and Industrial Temperature Ranges)

Symbol	Parameter	Test Conditions	Min.	Max.	Unit
Lu	Input Leakage Current	V_{DD} = Max., VIN = GND to VDD	—	5	μA
Ilo	Output Leakage Current	$V_{DD} = Max., \overline{CS} = V_{IH}, V_{OUT} = GND to V_{DD}$	—	5	μA
Vol	Output Low Voltage	Iol = 8mA, Vdd = Min.	—	0.4	V
Vон	Output High Voltage	$I_{OH} = -4mA$, $V_{DD} = Min$.	2.4		V
				Ş	973 thi 05

Commercial and Industrial Temperature Ranges

3873 tbl 06

DC Electrical Characteristics^(1, 2)

(VDD = Min. to Max., VLC = 0.2V, VHC = VDD - 0.2V)

		71V124SA10	71V124SA12		71V124SA15		
Symbol	Parameter	Commercial	Com'l	Ind	Com'l	Ind	Unit
lcc	$\frac{Dy}{CS} \leq V_{LC}, \text{ Outputs Open, } V_{DD} = Max., f = f_{MAX}^{(3)}$	145	130	140	100	120	mA
lsb	$\frac{Dynamic}{CS} \geq V_{HC}, \ Outputs \ Open, \ V_{DD} = Max., \ f = f_{MAX}^{(3)}$	45	40	40	35	40	mA
ISB1	$\label{eq:standby} \frac{Full}{CS} \geq V_{HC}, \ Outputs \ Open, \ V_{DD} = Max., \ f = 0^{(3)}$	10	10	10	10	10	mA

NOTES:

1. All values are maximum guaranteed values.

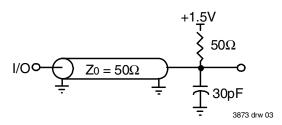
2. All inputs switch between 0.2V (Low) and VDD-0.2V (High).

3. fmax = 1/trc (all address inputs are cycling at fmax); f = 0 means no address input lines are changing.

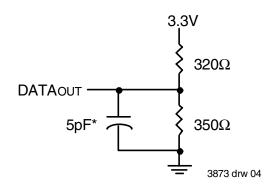
AC Test Conditions

Input Pulse Levels	GND to 3.0V
Input Rise/Fall Times	3ns
Input Timing Reference Levels	1.5V
Output Reference Levels	1.5V
AC Test Load	See Figure 1 and 2
	3873 tbl 07









*Including jig and scope capacitance.

Figure 2. AC Test Load (for tclz, tolz, tchz, tohz, tow, and twhz)

AC Electrical Characteristics

(VDD = Min. to Max., Commercial and Industrial Temperature Ranges)

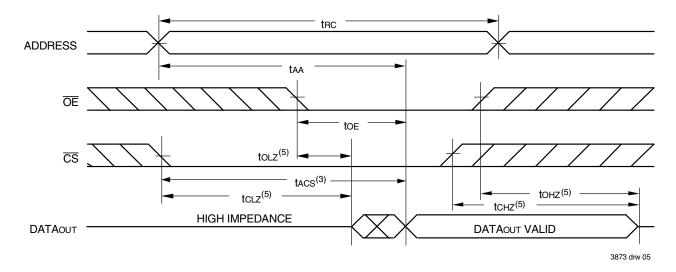
		71V12	4SA10	71V124SA12		71V124SA15		
Symbol	Parameter	Min.	Мах.	Min.	Max.	Min.	Мах.	Unit
READ CY	CLE							
trc	Read Cycle Time	10		12		15		ns
taa	Address Access Time	_	10		12		15	ns
tacs	Chip Select Access Time	—	10		12		15	ns
tclz ⁽¹⁾	Chip Select to Output in Low-Z	4		4		4		ns
tchz ⁽¹⁾	Chip Deselect to Output in High-Z	0	5	0	6	0	7	ns
toe	Output Enable to Output Valid	—	5		6		7	ns
tolz ⁽¹⁾	Output Enable to Output in Low-Z	0	—	0		0		ns
tонz ⁽¹⁾	Output Disable to Output in High-Z 0		5	0	5	0	5	ns
toн	Output Hold from Address Change	4		4		4		ns
WRITE CY	/CLE							
twc	Write Cycle Time	10		12		15		ns
taw	Address Valid to End-of-Write	7		8		10		ns
tcw	Chip Select to End-of-Write	7		8		10		ns
tas	Address Set-up Time	0		0		0		ns
twp	Write Pulse Width	7		8		10		ns
twr	Write Recovery Time	0		0		0		ns
tow	Data Valid to End-of-Write	5		6		7		ns
tDH	Data Hold Time	0	_	0		0		ns
tow ⁽²⁾	Output Active from End-of-Write	3	—	3		3		ns
twnz ⁽²⁾	Write Enable to Output in High-Z	0	5	0	5	0	5	ns

NOTES:

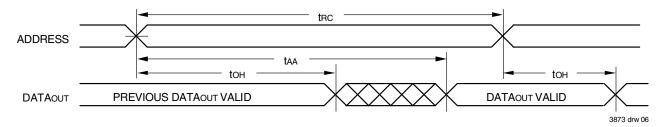
1. This parameter guaranteed with the AC load (Figure 2) by device characterization, but is not production tested.

3873 tbl 08

Timing Waveform of Read Cycle No. 1⁽¹⁾



Timing Waveform of Read Cycle No. 2^(1, 2, 4)

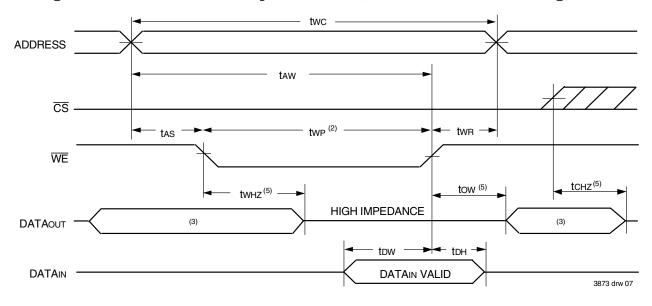


NOTES:

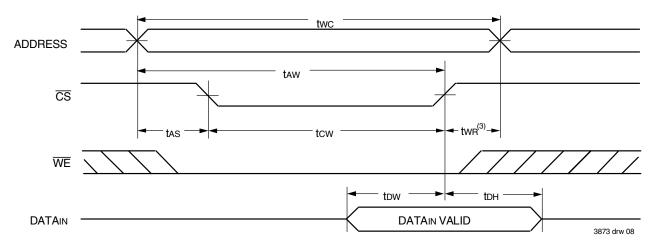
- 1. $\overline{\text{WE}}$ is HIGH for Read Cycle.
- 2. Device is continuously selected, \overline{CS} is LOW.
- 3. Address must be valid prior to or coincident with the later of CS transition LOW; otherwise taa is the limiting parameter.
- 4. \overline{OE} is LOW.
- 5. Transition is measured $\pm 200 \text{mV}$ from steady state.

Commercial and Industrial Temperature Ranges

Timing Waveform of Write Cycle No. 1 (WE Controlled Timing)^(1,2,4)



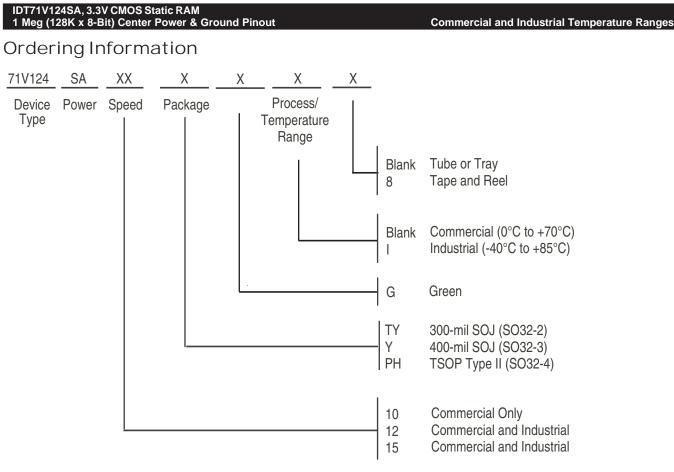
Timing Waveform of Write Cycle No. 2 (CS Controlled Timing)^(1, 4)



NOTES:

- 1. A write occurs during the overlap of a LOW \overline{CS} and a LOW \overline{WE} .
- OE is continuously HIGH. During a WE controlled write cycle with OE LOW, two must be greater than or equal to two to allow the I/O drivers to turn off and data to be 2. placed on the bus for the required tow. If OE is HIGH during a WE controlled write cycle, this requirement does not apply and the minimum write pulse is the specified twe. During this period, I/O pins are in the output state, and input signals must not be applied.
- 3.
- If the CSLOW transition occurs simultaneously with or after the WE LOW transition, the outputs remain in a high impedance state. CS must be active during the tcw write period. 4.

Transition is measured ±200mV from steady state. 5.



3873 drw 09

Datasheet Document History

11/22/99		Updated to new format
	Pg. 1–4, 7	Added Industrial Temperature range offerings
	Pg. 2	Added Recommended Operating Temperature and Supply Voltage table
	Pg. 6	Revised footnotes on Write Cycle No. 1 diagram
	Pg. 8	Added Datasheet Document History
08/30/00	Pg. 3	Tighten Icc and IsB
	Pg. 4	Tighten AC Characteristics toHz, tow and twHz
08/22/01	Pg. 7	Removed footnote "400-mil SOJ package only offered in 10ns and 12ns speed grade"
11/30/03	Pg. 1,3,7	Added Industrial temperature offering 10ns speed grade
01/30/04	Pg. 7	Added "Restricted hazardous substance device" to ordering information
2/14/07	Pg. 7	Added H generation die step to data sheet ordering information
10/13/08	Pg. 7	Removed "IDT" from the orderable part number
11/15/10	Pg. 1,3,4,7	Removed 20ns commercial, 10ns & 20ns industrial and also removed HSA offering
03/29/12	Pg. 7	Removed die step indicator from the ordering information
		Added tape and reel and green to the ordering information
02/19/13:	Pg. 1	Removed IDT reference to fabrication and changed fastest access address time from 9ns to 10ns



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